

**Notice of References Cited**

Application/Control No.

10/748,871

Applicant(s)/Patent Under  
Reexamination  
KIM ET AL.

Examiner

ASHER KHAN

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,969,719 A	10-1999	Tsujimoto, Taizou	715/727
*	B	US-2001/0055465 A1	12-2001	Inoue, Kenji	386/46
*	C	US-2001/0056434 A1	12-2001	Kaplan et al.	707/104.1
*	D	US-2002/0012522 A1	01-2002	Kawakami et al.	386/52
*	E	US-2002/0033889 A1	03-2002	Miyazaki, Takao	348/232
*	F	US-2002/0136539 A1	09-2002	Nakaya, Yoshihisa	386/125
*	G	US-2002/0141580 A1	10-2002	Okuyama, Takehiko	380/201
*	H	US-2003/0048848 A1	03-2003	Li et al.	375/240.25
*	I	US-2003/0123853 A1	07-2003	Iwahara et al.	386/69
*	J	US-2004/0001704 A1	01-2004	Chan et al.	386/96
*	K	US-6,833,848 B1	12-2004	Wolff et al.	715/719
*	L	US-7,315,389 B2	01-2008	Kuwata et al.	358/1.15
*	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

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